BARIŞ ARSLAN
ASST. PROF.

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Learning Knowledge

Doctorate 2003 - 2013	University of California, San Diego, Jacobs School of Engineering , Computer Science and Engineering, United States Of America
Postgraduate 2000 - 2002	University of California, San Diego, Jacobs School of Engineering, Computer Science and Engineering, United States Of America
Undergraduate 1996 - 2000	Ihsan Dogramaci Bilkent University, Faculty Of Engıneerıng, Department Of Computer Engıneerıng, Turkey

Foreign Languages

English, C2 Mastery

Dissertations

Doctorate, Adaptive Test Cost And Quality Optimization Through An Effective Yet Efficient Delivery Of Chip Specific Tests, University of California, San Diego, Jacobs School of Engineering, Computer Science and Engineering, 2013

Academic Titles / Tasks

Assistant Professor 2021 - Continues	Acibadem Mehmet Ali Aydinlar University, Faculty Of Engineering and Natural Sciences, Computer Engineering

Supported Projects

1. Arslan B., TUBITAK Project, Gerçek Zamanlı Test Veri Analizi ile Test Optimizasyonu, 2018 - 2022
2. Arslan B., TUBITAK Project, Entegre Devre Zamanlamasını etkileten Küçük Boyutlu Üretim Hatalarının Tanılanması, 2015 - 2017

Published journal articles indexed by SCI, SSCI, and AHCI

1. **Aggressive Test Cost Reductions Through Continuous Test Effectiveness Assessment**
   Arslan B., Orailoglu A.
   IEEE TRANSACTIONS ON COMPUTER-AIDED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS, vol.35, no.12, pp.2093-2103, 2016 (SCI-Expanded)
2. **Power-Aware Delay Test Quality Optimization for Multiple Frequency Domains**

Arslan B., Orailoglu A.

IEEE TRANSACTIONS ON COMPUTER-AIDED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS, vol.35, no.1, pp.141-154, 2016 (SCI-Expanded)

Books & Book Chapters

1. **Creating Ad Campaigns Using Generative AI**
   Bulut A., Arslan B.
   in: Applications of Generative AI, Zhihan Lyu, Editor, Springer Nature, Zug, pp.22-36, 2024

Refereed Congress / Symposium Publications in Proceedings

1. **Test Cost-Test Quality Modeling For Adaptive Test**
   Demiray B. Z., Arslan B.
   2022 IEEE INTERNATIONAL CONFERENCE ON AUTOMATION, QUALITY AND TESTING, ROBOTICS (AQTR), Cluj-Napoca, Romania, 19 - 21 May 2022, pp.1-6

2. **Small Delay Defect Diagnosis through Failure Observation Ordering**
   ARSLAN B.
   PROCEEDING OF 2016 IEEE INTERNATIONAL CONFERENCE ON AUTOMATION, QUALITY AND TESTING, ROBOTICS (AQTR), Cluj-Napoca, Romania, 19 - 21 May 2016, pp.67-72

3. **Full Exploitation of Process Variation Space for Continuous Delivery of Optimal Delay Test Quality**
   Arslan B., Orailoglu A.
   18th Asia and South Pacific Design Automation Conference (ASP-DAC), Yokohama, Japan, 22 - 25 January 2013, pp.552-557

4. **Tracing the Best Test Mix through Multi-Variate Quality Tracking**
   Arslan B., Orailoglu A.
   IEEE 31st VLSI Test Symposium (VTS), California, United States Of America, 29 April - 02 May 2013

5. **Delay Test Resource Allocation and Scheduling for Multiple Frequency Domains**
   Arslan B., Orailoglu A.
   30th IEEE VLSI Test Symposium (VTS), Hawaii, United States Of America, 23 - 25 April 2012, pp.114-119

6. **Adaptive Test Optimization through Real Time Learning of Test Effectiveness**
   Arslan B., Orailoglu A.
   Design, Automation and Test in Europe Conference (DATE), Grenoble, France, 14 - 18 March 2011, pp.1430-1435

7. **Adaptive Test Framework for Achieving Target Test Quality at Minimal Cost**
   Arslan B., Orailoglu A.
   20th Asian Test Symposium (ATS), New Delhi, India, 20 - 23 November 2011, pp.323-328

8. **Delay Test Quality Maximization through Process-aware Selection of Test Set Size**
   Arslan B., Orailoglu A.
   IEEE International Conference on Computer Design, Amsterdam, Netherlands, 3 - 06 October 2010, pp.390-395

9. **Test cost reduction through a reconfigurable scan architecture**
   Arslan B., Orailoglu A.
   35th International Test Conference, Charlottetown, Canada, 26 - 28 October 2004, pp.945-952

10. **Extending the applicability of parallel-serial scan designs**
    Arslan B., Sinanoglu O., Orailoglu A.
    IEEE International Conference on Computer Design, San-Jose, Costa Rica, 11 - 13 October 2004, pp.200-203

11. **CircularScan: A scan architecture for test cost reduction**
    Arslan B., Orailoglu A.
    Design, Automation and Test in Europe Conference and Exhibition (DATE 04), Paris, France, 16 - 20 February 2004, pp.1290-1295

12. **Design space exploration for aggressive test cost reduction in circular scan Architectures**
    Arslan B., Orailoglu A.
    International Conference on Computer Aided Design (ICCAD 2004), San-Jose, Costa Rica, 7 - 11 November 2004, pp.726-731
13. **Extracting precise diagnosis of bridging faults from stuck-at fault information**
    Arslan B., Orailoglu A.
    12th Asian Test Symposium, Xian, China, 16 - 19 November 2003, pp.230-235
14. **Fault dictionary size reduction through test response superposition**
    Arslan B., Orailoglu A.
    20th IEEE International Conference on Computer Design, Freiburg, Germany, 16 - 18 September 2002, pp.480-485

Academic and Administrative Experience

2018 - 2021	**Head of Department**	Istanbul Sehir University, Institute Of Science, Electrical and Computer Engineering Department

Metrics

Publication: 17
Citation (WoS): 85
Citation (Scopus): 103
H-Index (WoS): 4
H-Index (Scopus): 5

Research Areas

Computer Sciences, Artificial Intelligence, Computer Learning and Pattern Recognition

Non Academic Experience

Company, OakNorth, Data Science
Company, QUALCOMM INC., Engineering
Company, Marvell Technology, Inc., Engineering
Company, Intel Corporation, Engineering